



2877

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): SHING LEE ET AL.
Title: SYSTEM FOR MEASURING POLARIMETRIC SPECTRUM AND
OTHER PROPERTIES OF A SAMPLE
Serial No.: 09/778,245 Filing Date: February 6, 2001
Examiner: Unknown Group Art Unit: 2877
Docket No.: M-10685-1P US

San Jose, California
August 8, 2001

COMMISSIONER FOR PATENTS
Washington, D.C. 20231

**INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR § 1.97(b)**

Dear Sir:

Pursuant to 37 C.F.R. § 1.56, § 1.97 and § 1.98, the documents listed on the accompanying form PTO-1449 are called to the attention of the Examiner for the above patent application. Copies of these documents are enclosed.

Citation of these documents shall not be construed as:

1. an admission that the documents are necessarily prior art with respect to the instant invention;
2. a representation that a search has been made; or
3. an admission that the information cited herein is, or is considered to be, material to patentability as defined in § 1.56(b).

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231, on August 8, 2001.

Tammy L. Kaplan

Tammy L. Kaplan

Date of Signature

Respectfully submitted,

James S. Hsue

James S. Hsue
Attorney for Applicant(s)
Reg. No. 29,545

RECEIVED
AUG 16 2001
TECHNOLOGY CENTER

LAW OFFICES OF
SKJERVEN MORRILL
MacPHERSON LLP

25 METRO DRIVE
SUITE 700
SAN JOSE, CA 95110
(408) 453-9200
FAX (408) 453-7979